

Substitute Form PTO-1449 (Modified) DEC 02 2002 Information Disclosure Statement by Applicant (Use separate sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-213002	Application No. 09/455,991
	Applicant Ohtani, et al.		
	Filing Date December 6, 1999	Group Art Unit 2815	

U.S. Patent Documents


Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>D</i>	AA	6 365 933	Apr 2, 2002	Yamazaki et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
<i>D</i>	AQ	O. Schoenfeld et al., "Crystallization of amorphous silicon by NiSi ₂ precipitates." Thin Solid Films 261 (1995) 236-240.
	AR	
	AS	
	AT	

Examiner Signature 	Date Considered 1/23/02
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Disclosure Form (PTO-1449)

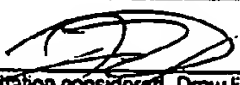
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PATENT MARK OFF

Substitute Form PTO-1449 (Patent Examined) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-213002	Application No. 09/455,991
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U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>D</i>	AA	5 569 936	Oct 29, 1996	Zhang et al.			
<i>D</i>	AB	5 591 987	Jan 7, 1997	Yamazaki et al.			
<i>D</i>	AC	5 608 232	Mar 4, 1997	Yamazaki et al.			
<i>D</i>	AD	5 614 732	Mar 25, 1997	Yamazaki			
<i>D</i>	AE	5 627 384	May 6, 1997	Teramoto et al.			
<i>D</i>	AF	5 639 698	Jun 17, 1997	Yamazaki et al.			
<i>D</i>	AG	5 646 424	Jul 8, 1997	Zhang et al.			
<i>D</i>	AH	5 677 549	Oct 14, 1997	Takayama et al.			
<i>D</i>	AI	5 696 386	Dec 9, 1997	Yamazaki			
<i>D</i>	AJ	5 717 224	Feb 10, 1998	Zhang			
<i>D</i>	AK	5 763 899	Jun 9, 1998	Yamazaki et al.			
<i>D</i>	AL	5 814 540	Sep 29, 1998	Takemura et al.			
<i>D</i>	AM	5 821 138	Oct 13, 1998	Yamazaki et al.			
<i>D</i>	AN	5 821 563	Oct 13, 1998	Yamazaki et al.			
<i>D</i>	AO	5 869 363	Feb 9, 1999	Yamazaki et al.			
<i>D</i>	AP	5 888 858	Mar 30, 1999	Yamazaki et al.			
<i>D</i>	AQ	5 897 374	Apr 27, 1999	Lin			
<i>D</i>	AR	6 207 969	Mar 27, 2001	Yamazaki			

Foreign Patent Documents or Published Foreign Patent Applications								
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							Yes	No
	AS							
	AT							
	AU							
	AV							
	AW							

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